

# C-MOS Circuit Parametrics

Last updated 4/12/22

# C-MOS Circuits

• Parameters

$$K_n = \frac{W\mu_n C_{ox}}{2L} \qquad K_p = \frac{W\mu_p C_{ox}}{2L}$$
$$K_n = \frac{k'_n W}{2L} \qquad k'_n = \mu_n C_{ox} \qquad K_p = \frac{k'_p W}{2L} \qquad k'_p = \mu_p C_{ox}$$

$\mu_n, \mu_p, C_{ox}$  fixed for a given semiconductor process  $\rightarrow$

$k'_n, k'_p$  fixed for a given semiconductor process

$$I_D = K_n [2(V_{GS} - V_{tn})V_{DS} - V_{DS}^2]$$

$$I_D = \frac{k'_n W}{2L} [2(V_{GS} - V_{tn})V_{DS} - V_{DS}^2]$$

$$V_{DSsat} = V_{GS} - V_{th}$$

$$I_D = K_n (V_{GS} - V_{tn})^2$$

$$I_D = \frac{k'_n W}{2L} (V_{GS} - V_{tn})^2$$

$$C_{Gn} = W \times L \times k'_n / \mu_n$$

$$I_D = K_p [2(V_{SG} - V_{tp})V_{SD} - V_{SD}^2]$$

$$I_D = \frac{k'_p W}{2L} [2(V_{SG} - V_{tp})V_{SD} - V_{SD}^2]$$

$$V_{SDsat} = V_{SD} - V_{th}$$

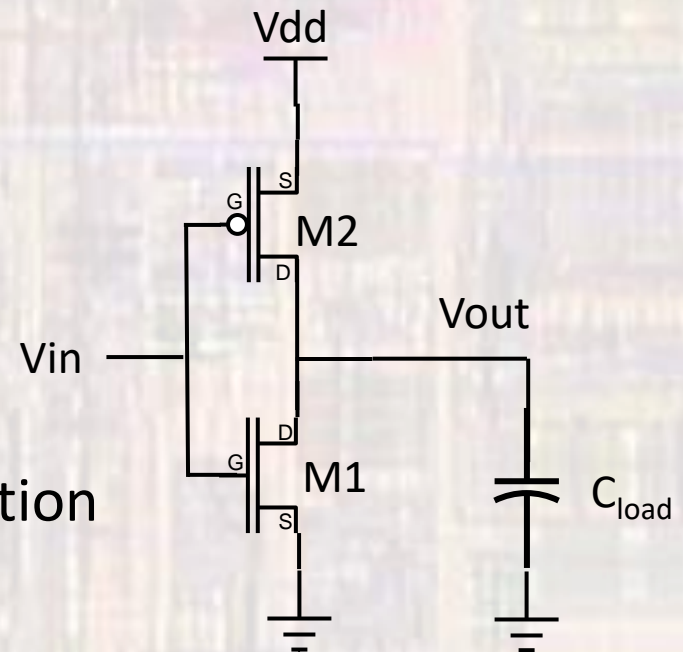
$$I_D = K_p (V_{SG} - V_{tp})^2$$

$$I_D = \frac{k'_p W}{2L} (V_{SG} - V_{tp})^2$$

$$C_{Gp} = W \times L \times k'_p / \mu_p$$

# C-MOS Circuits

- Switching speeds
  - Midpoint in to midpoint out
    - $t_{phl}$ ,  $t_{plh}$
  - Assume only one device active
    - Charging/discharging the capacitor
- Devices start in saturation and transition to non-saturation



# C-MOS Circuits

- Switching speeds
  - Super simple estimation
    - Assume in saturation upto the switching point

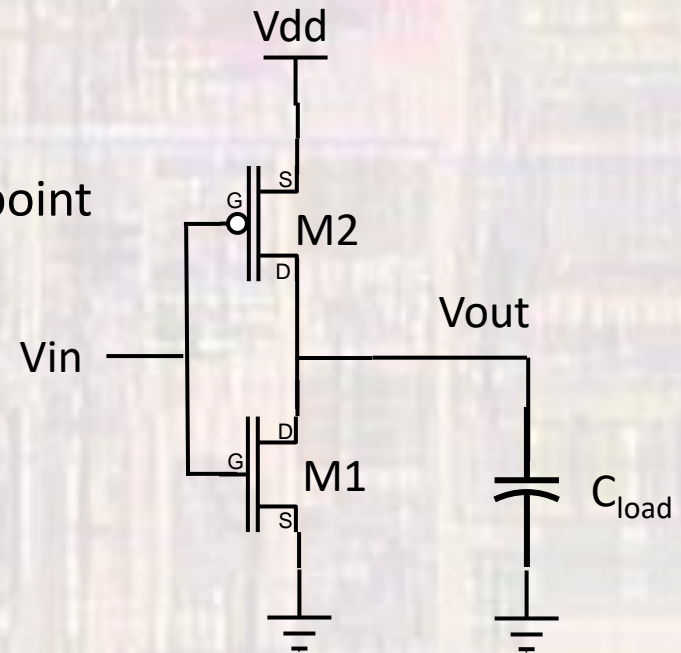
$$I = C \frac{dv}{dt} = \frac{k'_n W}{2 L} (V_{gs} - V_t)^2$$

$$I = C \frac{dv}{dt} = \frac{k'_n W}{2 L} (V_{dd} - V_t)^2$$

$$dt = C \frac{1}{\frac{k'_n W}{2 L} (V_{dd} - V_t)^2} dv$$

$$t_{nl} = C \frac{1}{\frac{k'_n W}{2 L} (V_{dd} - V_t)^2} \frac{V_{dd}}{2}$$

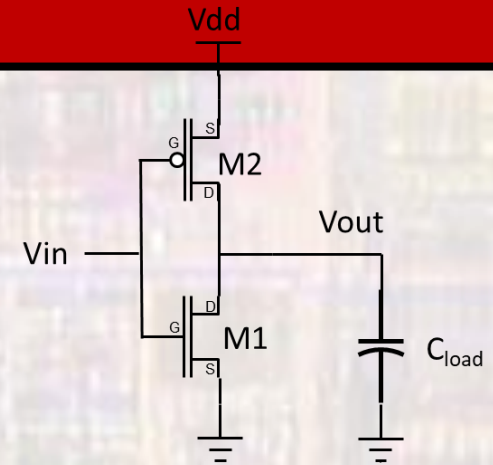
$$t_{pd} = t_{nl} + t_{lh}$$



$$t_{lh} = C \frac{1}{\frac{k'_p W}{2 L} (V_{dd} - V_t)^2} \frac{V_{dd}}{2}$$

# C-MOS Circuits

- Switching speeds
  - Super simple estimation
    - Assume in saturation upto the switching point



$$t_{hl} = C \frac{1}{\frac{k'_n W}{2} \frac{V_{dd} - V_t}{L}} \frac{V_{dd}}{2}$$

$$t_{lh} = C \frac{1}{\frac{k'_p W}{2} \frac{V_{dd} - V_t}{L}} \frac{V_{dd}}{2}$$

$$t_{pd} = t_{hl} + t_{lh}$$

- Assuming N and P matched for switching point

$$t_{pd} = \frac{C V_{dd}}{\frac{k'_n W}{2} \frac{V_{dd} - V_t}{L}}$$

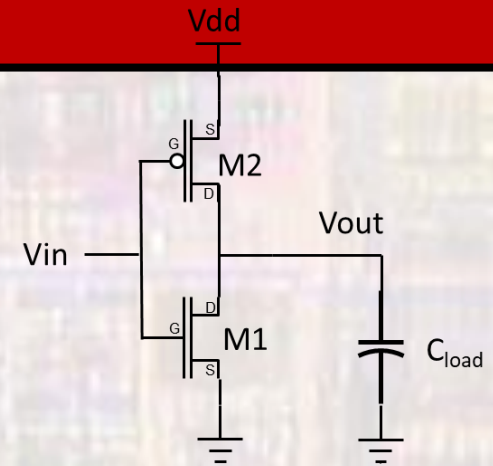
# C-MOS Circuits

- Switching speeds
  - Super simple estimation
    - Assume in saturation upto the switching point
  - Matched devices

$$t_{pd} = \frac{C_{load} V_{dd}}{\frac{k'_n W}{2} \frac{V_{dd}}{L} (V_{dd} - V_t)^2}$$

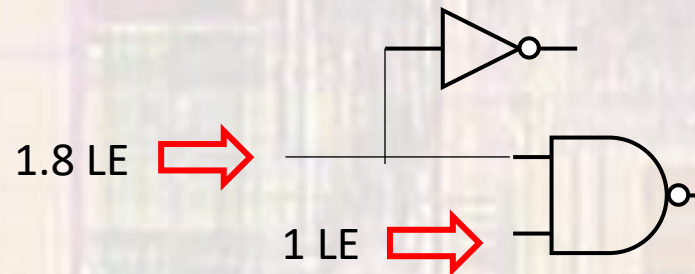
- Reduce  $t_{pd}$ 
  - Increase  $V_{dd}$
  - Increase  $W/L$
  - Decrease  $C_{load}$

Increasing  $V_{dd}$  reduces gate delays  
→ higher operating frequency



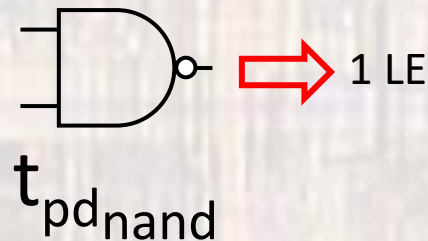
# Logic Timing

- Gate level timing
  - Each gate **input** has an equivalent input load factor
    - Models the input capacitance
    - Load equivalent (LE)
    - Technology / Process dependent



# Logic Timing

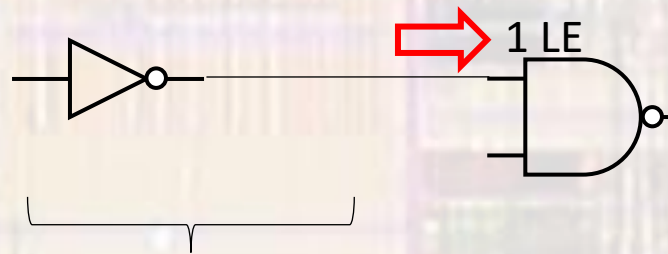
- Gate level timing
  - Each gate has internal delay
    - Assumes a fixed external load – 1 LE
    - Circuit dependent – but fixed
    - Technology / Process dependent





# Logic Timing

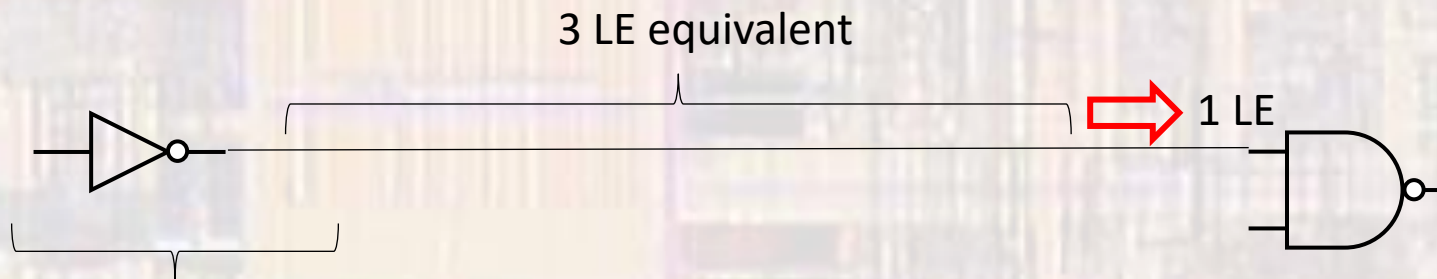
- Gate level timing
  - Each gate has a variable delay factor -  $r$ 
    - Function of the gate's drive capability
    - Modifies the circuit delay based on the amount of loading
    - Circuit dependent



$$t_{pd_{inv}} + r \times 1 \text{ LE}$$

# Logic Timing

- Gate level timing
  - Long wires have enough capacitance to impact delays
    - Model long wires in terms of load equivalents (LEs)
    - Modifies the circuit delay based on the amount of loading
    - Circuit dependent



$$t_{pd_{inv}} + r \times (3 \text{ LE} + 1 \text{ LE})$$

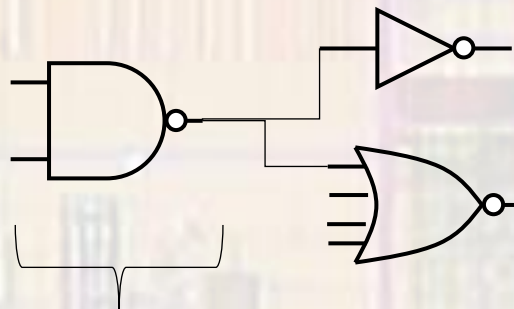
# Digital Circuit Timing

- Gate level timing

$$t_{pd} = t_{\text{fixed\_delay}} + r_{\text{variable\_delay\_factor}} * \text{Load Equivalents}$$

Standard

Gate	INV	2-NAND	2-NOR	4-NAND	4-NOR
Input load factor (LE)	0.8	1.0	2.0	1.66	3.33
Fixed delay factor	50ps	65ps	65ps	80ps	80ps
Variable delay factor	5ps/LE	8ps/LE	8ps/LE	12ps/LE	12ps/LE



$$t_{pd} = 65\text{ps} + 8\text{ps/LE} * (0.8\text{LE} + 3.33\text{LE}) = 98\text{ps}^{**}$$

\*\* we are assuming interconnect capacitance is negligible

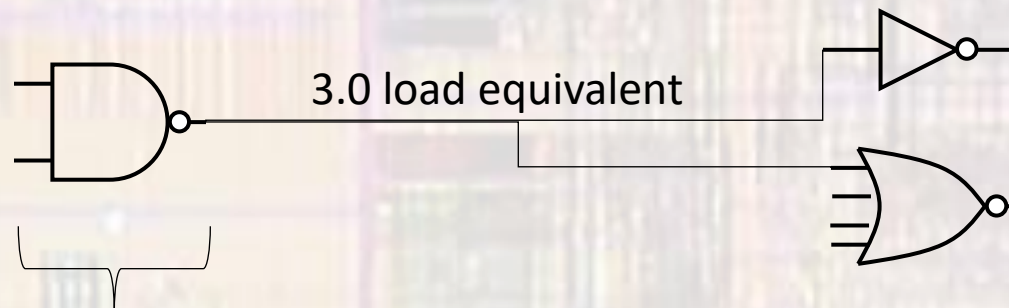
# Digital Circuit Timing

- Gate level timing

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Standard

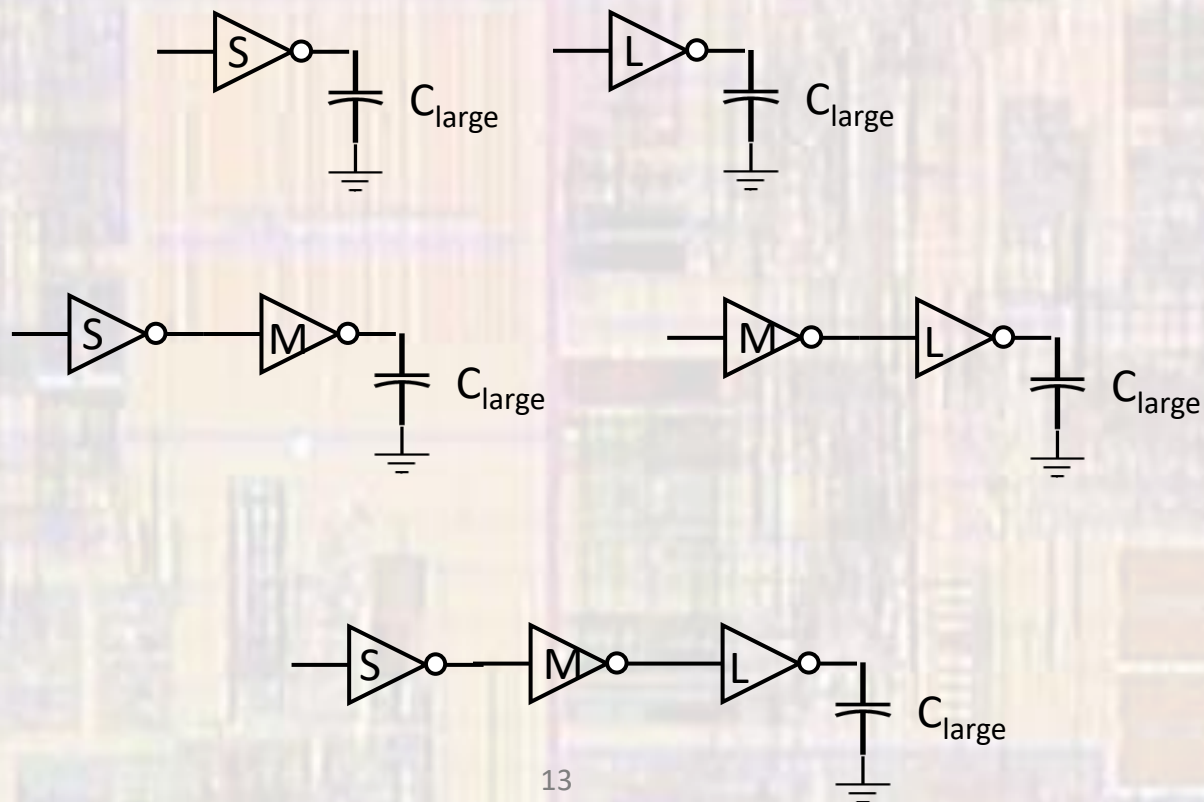
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Variable delay factor	5ps/LE	8ps/LE	8ps/LE	12ps/LE	12ps/LE



$$t_{pd} = 65ps + 8ps/LE * (0.8LE + 3.33LE + 3.0LE) = 122ps$$

# Digital Circuit Timing

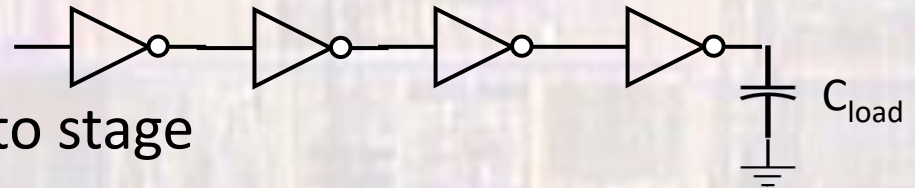
- Driving a Large Capacitive Load
  - Clk signals
  - Long wires
  - External circuitry



# Digital Circuit Timing

- Driving a Large Capacitive Load

- $N$  – number of stages
- $s$  – scale factor from stage to stage
- $C_{inv}$  – base inverter input capacitance
- $C_{load}$  – load capacitance
- $\gamma$  – Ratio of an inverters output capacitance to input capacitance (Typically  $\leq 1$ )
- $t_{p0}$  – base inverter delay

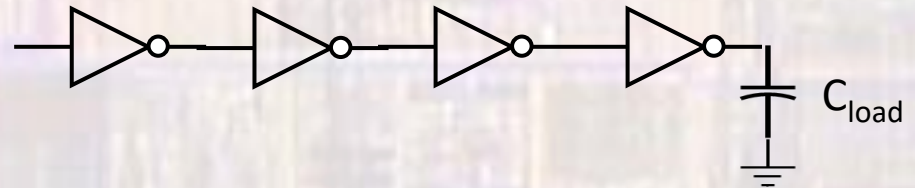


$$s = \sqrt[N]{C_{load} / C_{inv}}$$

$$t_{pd} = N t_{p0} \left( 1 + \frac{\sqrt[N]{C_{load} / C_{inv}}}{\gamma} \right)$$

# Digital Circuit Timing

- Driving a Large Capacitive Load
  - How many stages?



$$s_{opt} = \exp\left(1 + \gamma/s_{opt}\right)$$

- Only has an analytic solution for  $\gamma = 0$

$$s_{opt} = e = 2.718 \quad N_{opt} = \ln\left(C_{load}/C_{inv}\right)$$

- For the more realistic value of  $\gamma = 1$

$$s_{opt} \approx 3.6 \quad N_{opt} = \log_{3.6}\left(C_{load}/C_{inv}\right)$$

# C-MOS Circuits

- Power

- DC power

- Junction leakage (S/D to Body)
      - Becomes important for large designs
      - Power  $\propto V_{dd}$

- Switching Power

- Charging / Dis-charging the load

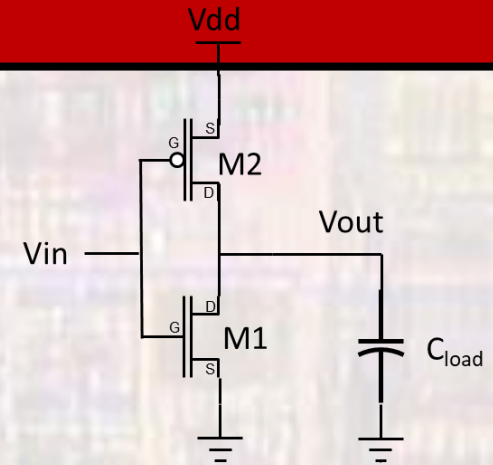
$$E = \int_0^{\infty} i(t)V_{out}dt = \int_0^{\infty} C \frac{dv}{dt} V_{out}dt = \int_0^{V_{dd}} CV_{out}dv = \frac{1}{2} CV_{dd}^2$$

- Rising and falling

$$E = CV_{dd}^2$$

$$P = CV_{dd}^2 F$$

Power is a sq function of Vdd





# C-MOS Circuits

- Power

- Shoot-Through

- Short period of time when both devices are on
- Current from Vdd to Gnd
- Can cause noise in Vdd and Gnd

$$P = I_{peak} V_{dd} \left( \frac{t_r + t_f}{2} \right) F$$

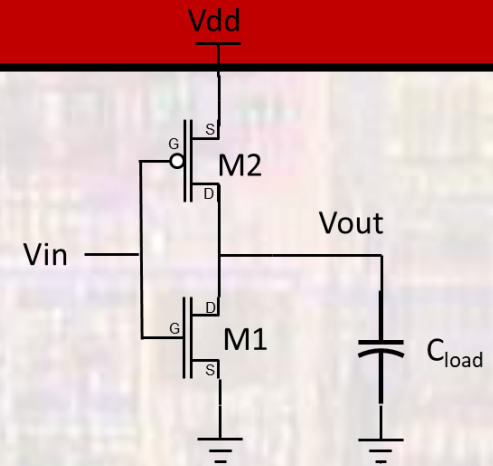
- Total power

- $\alpha$  – proportion of clock intervals actually switching
- $\beta$  – leakage factor

$$P = P_{DC} + P_{SW} + P_{Shoot}$$

All terms a function of Vdd

$$P = \beta V_{DD} + \alpha C V_{dd}^2 F + \alpha I_{peak} V_{dd} \left( \frac{t_r + t_f}{2} \right) F$$

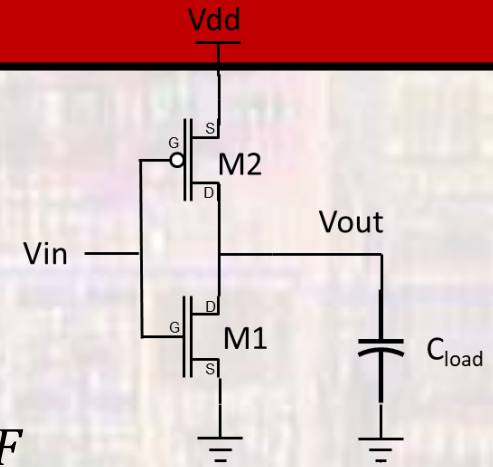


# C-MOS Circuits

- Power – Speed Tradeoff

$$P = \beta V_{DD} + \alpha C V_{dd}^2 F + \alpha I_{peak} V_{dd} \left( \frac{t_r + t_f}{2} \right) F$$

$$t_{pd} = \frac{C_{load} V_{dd}}{\frac{k'_n W}{2} \frac{V_{dd} - V_t}{L}}$$



Power goes up as  $V_{dd}^3$  when optimizing for peak speed